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PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

Naotoshi KIRIHARA et al

Serial No.: 10/593091

Filed: September 15, 2006

For: A LASER IONIZATION MASS
SPECTROMETER

INFORMATION DISCLOSURE STATEMENT

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

As a means of complying with the duty of disclosure under 37 CFR §1.56, and in accordance with 37 CFR §§1.97 and 1.98, Applicant(s), through the undersigned attorney, submits this Information Disclosure Statement. The patents, publications or other information submitted herewith are listed on the attached Form PTO-1449 and copies are attached excluding U.S. patents and publications.

Documents AA and AE-AH listed on the attached Form PTO-1449 were cited in the International Search Report. A copy of the ISR is attached.

Documents AF and AI-AM listed on the attached Form PTO-1449 are discussed on pages 1, 2 and 3 of the instant specification.

In accordance with 37 CFR §1.97(b)(3), this Information Disclosure Statement is being filed before the mailing date of a first Office Action on the merits of the above-identified application.

Should any additional fee be required by the filing of this statement, please charge such fee to Deposit Account No. 06-1358.

Respectfully submitted,

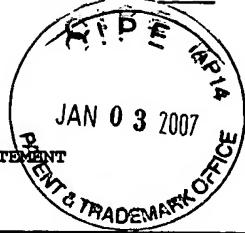
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Date: January 3, 2007

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LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT

ATTY. DOCKET NO.: P71443US0
SERIAL NO.: 10/593091
APPLICANT(S): KIRIHARA et al

GROUP ART UNIT: _____
FILING DATE: September 15, 2006
TODAY'S DATE: January 3, 2007

U. S. PATENT DOCUMENTS

*EXAMINER <u>INITIAL</u>	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE (If Appropriate)
AA	<u>5629518</u>	<u>05/13/97</u>	<u>Grotheer et al</u>	<u>250</u>	<u>288</u>	_____
AB	_____	_____	_____	_____	_____	_____
AC	_____	_____	_____	_____	_____	_____
AD	_____	_____	_____	_____	_____	_____

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION (YES) (NO)
AE	<u>4441972A1</u>	<u>08/14/96</u>	<u>Germany</u>	_____	_____	XX
AF	<u>8-222181</u>	<u>08/30/96</u>	<u>Japan</u>	_____	_____	XX
AG	<u>2001-108657</u>	<u>04/20/01</u>	<u>Japan</u>	_____	_____	XX

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

AH	<u>RIMMPA, 10th, 2001, pgs. 546-547</u>
AI	<u>Scoles, ATOMIC AND MOLECULAR BEAM METHODS, Basic Techniques, Oxford Univ. Press, 1988, pgs. 62-68</u>
AJ	<u>Smith, Jr. et al, TRANS OF THE ASME, Dec 1962, pgs. 434-446, A Theoretical Method fo Determining Discharge Coefficients for...</u>
AK	<u>Hayes, CHEM. REV. 87, 1987, pgs. 745-760, Analytical Spectroscopy in Supersonic Expansions</u>
AL	<u>Saenger et al, J. CHEM. PHYS. 79, Dec 15, 1983, pgs. 6043-6045, On the time required to reach fully developed flow in pulsed...</u>
AM	<u>Suzuki et al, ANALYTICAL SCI. 2001, Vol 17 Suppl., pgs. i563-I-566, A New Laser Mass Spectrometry for Chemical Ultratrace...</u>

EXAMINER	DATE CONSIDERED
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* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant(s)